



Attorney Docket No. 03506/LH



**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Ryouichi YOKOYAMA et al
Serial No. : 10/650,059
Filed : August 27, 2003
For : STRESS MEASUREMENT METHOD
USING X-RAY DIFFRACTION
Art Unit : 2855
Examiner : Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT - II
WITH STATEMENT UNDER 37 CFR 1.97(e)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

Submitted herewith are the following:

- (1) Copy of a European Search Report dated April 28, 2004, issued in the counterpart European application;
- (2) Copies of the cited publications (except for Tanaka et al., A METHOD OF X-RAY STRESS MEASUREMENT FOR CUBIC POLYCRYSTALS WITH FIBER TEXTURE, which is included in the IDS - I filed concurrently herewith); and
- (3) Forms PTO/SB/08A and PTO/SB/08B. It is requested that initialed copies of the Forms PTO/SB/08A and PTO/SB/08B be returned to indicate that the publications listed therein have been considered and made of record.

Said communication is in English, thereby satisfying the requirements for a concise explanation of relevance for any non-English language publications cited therein (MPEP 609 III A(3)).

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on the date noted below.

Patricia O. Bryson
Patricia O. Bryson

Dated: June 17, 2004

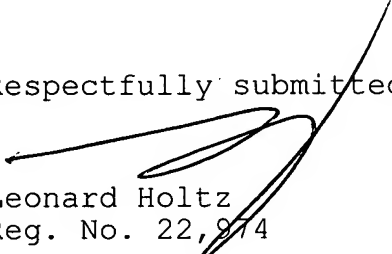
In the event that this Paper is late filed, and the necessary petition for extension of time is not filed concurrently herewith, please consider this as a Petition for the requisite extension of time, and to the extent not tendered by check attached hereto, authorization to charge the extension fee, or any other fee required in connection with this Paper, to Account No. 06-1378.

STATEMENT UNDER 37 CFR 1.97(e) (1)

Each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the present Information Disclosure Statement. Said Communication bears a mailing date of April 28, 2004. Therefore, the filing of this Information Disclosure Statement is timely under the provisions of 37 CFR 1.97(e) and does not require a fee.

It is respectfully requested that the attached publications be considered and made of record.

Respectfully submitted,


Leonard Holtz
Reg. No. 22,974

June 17, 2004

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PTO/SB/08A (08-00)

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Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	10/650,059
				Filing Date	August 27, 2003
				First Named Inventor	Ryouichi YOKOYAMA et al
				Group Art Unit	2855
				Examiner Name	
Sheet	1	of	2	Attorney Docket Number	03506/LH

U.S. PATENT DOCUMENTS

Exam. Inits [*]	Cite No ¹	Document Number	Kind Code ²	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion

FOREIGN PATENT DOCUMENTS

Exam Inits [*]	Cite No ¹	Offc	Document Number ⁴	Kind Code ⁵	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion	T ⁶
	1	DE	197 19 473	A1	FRAUNHOFER GES FORSCHUNG	04-02-1998		

Examiner Signature		Date Considered	
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^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Place a check here if English translation is attached.

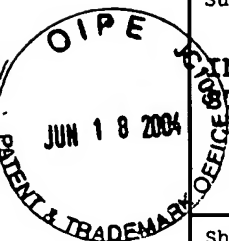
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				Group Art Unit		2855	
				Examiner Name			
Sheet	1	of	2	Attorney Docket Number		03506/LH	
OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS							
Examiner Initials	Cite No. ¹	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published					T ²
	2	Tanaka et al., "X-ray residual stress measurement of aluminum thin films with 111 fiber texture" Journal of the Society of Materials Science, Japan, Soc. Mater. Sci. Japan, Japan, Vol. 45, No. 10, pages 1138-1144, XP00902646, ISSN: 0514-5163, October 1996.					
	3	Lappalainen J. Et al., "Electrical and Mechanical Properties of Ferroelectric Thin Films Laser Ablated from a PBO.97NDO.02 (ZRO.55TI0.45)O3 Target" Journal of Applied Physics, American Institute of Physics. New York, US, Vol. 82, No. 7, pages 3469-3477, XP000738070, ISSN: 0021-8979, October 1, 1997.					
Examiner Signature					Date Considered		

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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